

Resource Summary Report

Generated by [RRID](#) on Apr 8, 2025

Rensselaer Polytechnic Institute; New York; USA

RRID:SCR_011492

Type: Tool

Proper Citation

Rensselaer Polytechnic Institute; New York; USA (RRID:SCR_011492)

Resource Information

URL: <http://rpi.edu/>

Proper Citation: Rensselaer Polytechnic Institute; New York; USA (RRID:SCR_011492)

Abbreviations: RPI

Synonyms: RPI

Resource Type: university, institution

Funding:

Resource Name: Rensselaer Polytechnic Institute; New York; USA

Resource ID: SCR_011492

Record Creation Time: 20220129T080305+0000

Record Last Update: 20250407T215917+0000

Ratings and Alerts

No rating or validation information has been found for Rensselaer Polytechnic Institute; New York; USA.

No alerts have been found for Rensselaer Polytechnic Institute; New York; USA.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We found 1 mentions in open access literature.

Listed below are recent publications. The full list is available at [RRID](#).

Ljosa V, et al. (2009) Introduction to the quantitative analysis of two-dimensional fluorescence microscopy images for cell-based screening. PLoS computational biology, 5(12), e1000603.